

APPENDIX F: TEST PROCEDURES FOR SUB6 NR + NR RADIO

Appendix F provides the test procedures for validating Qualcomm Smart Transmit feature for Sub6 NR standalone (SA) and LTE + Sub6 NR non-standalone (NSA) mode transmission scenario, where sub-6GHz LTE link acts as an anchor.

SAR exposure switch validation with one simultaneous transmission scenario (i.e., either FR1 NSA or LTE interband ULCA) is sufficient as Smart Transmit operation is the same.

NOTE: If `multi_Tx_factor` is set to > 1.0 with EFS version 19 (or higher), then in single Tx transmission scenarios, Smart Transmit ensures time-averaged RF exposure is \leq $(\text{SAR_design_target} * 10 + \text{sub6 device uncertainty}/10) <$ regulatory RF exposure limit for sub6 radio managed by Smart Transmit. In simultaneous Tx transmission scenarios, Smart Transmit ensures time-averaged RF exposure is \leq $(\text{SAR_design_target} * \text{multi_Tx_factor} * 10 + \text{sub6 device uncertainty}/10) <$ regulatory RF exposure limit for sub6 radios managed by Smart Transmit. These simultaneous transmission scenarios are listed below:

- 2-or-more radio scenarios within WWAN like EN-DC, LTE ULCA, etc.
- 2-or-more-radio across technologies such as WWAN+WLAN, WWAN+BT, WLAN+BT and WWAN+WLAN+BT transmission scenarios (if WLAN/BT radios are also managed by Smart Transmit).

F.1 Time-varying Tx power test for sub6 NR in SA mode

Follows Section 4.2.1 to select test configurations for time-varying test. This test is performed with two pre-defined test sequences (described in Section 4.1) applied to Sub6 NR. Follow the test procedures described in Section 4.3.1 to demonstrate the effectiveness of power limiting enforcement and that the time averaged Tx power of Sub6 NR when converted into 1gSAR values does not exceed the regulatory limit at all times (see Eq. (1a) and (1b)). Sub6 NR response to test sequence1 and test sequence2 will be similar to other technologies (say, LTE), and are shown in Sections 9.1.4.

F.2 Switch in SAR exposure between LTE vs. Sub6 NR during transmission

This test is to demonstrate that Smart Transmit feature accurately accounts for switching in exposures among SAR for LTE radio only, SAR from both LTE radio and sub6 NR, and SAR from sub6 NR only scenarios, and ensures total time-averaged RF exposure compliance with FCC limit.

Test procedure:

1. Measure conducted Tx power corresponding to P_{limit} for LTE and sub6 NR in selected band. Test condition to measure conducted P_{limit} is:
 - Establish device in call with the callbox for LTE in desired band. Measure conducted Tx power corresponding to LTE P_{limit} with Smart Transmit peak exposure mode enabled, and callbox set to request maximum power.
 - Repeat above step to measure conducted Tx power corresponding to Sub6 NR P_{limit} . If testing LTE+Sub6 NR in non-standalone mode, then establish LTE+Sub6 NR call with

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callbox and request all down bits for radio1 LTE. In this scenario, with callbox requesting maximum power from Sub6 NR, measured conducted Tx power corresponds to radio2 P_{limit} (as radio1 LTE is at all-down bits)

2. Set DUT to the intended Smart Transmit exposure mode with EUT setup for LTE + Sub6 NR call. First, establish LTE connection in all-up bits with the callbox, and then Sub6 NR connection is added with callbox requesting UE to transmit at maximum power in Sub6 NR. As soon as the Sub6 NR connection is established, request all-down bits on LTE link (otherwise, Sub6 NR will not have sufficient RF exposure margin to sustain the call with LTE in all-up bits). Continue LTE (all-down bits)+Sub6 NR transmission for more than one time-window duration to test predominantly Sub6 NR SAR exposure scenario (as SAR exposure is negligible from all-down bits in LTE). After at least one time-window, request LTE to go all-up bits to test LTE SAR and Sub6 NR SAR exposure scenario. After at least one more time-window, drop (or request all-down bits) Sub6 NR transmission to test predominantly LTE SAR exposure scenario. Continue the test for at least one more time-window. Record the conducted Tx powers for both LTE and Sub6 NR for the entire duration of this test.
3. Once the measurement is done, extract instantaneous Tx power versus time for both LTE and Sub6 NR links. Similar to technology/band switch test in Section 4.3.3, convert the conducted Tx power for both these radios into 1gSAR value (see Eq. (6a) and (6b)) using corresponding technology/band P_{limit} measured in Step 1, and then perform 100s running average to determine time-averaged 1gSAR versus time as illustrated in Figure 4-1. Note that here it is assumed both radios have Tx frequencies < 3GHz, otherwise, 60s running average should be performed for radios having Tx frequency between 3GHz and 6GHz.
4. Make one plot containing: (a) instantaneous Tx power versus time measured in Step 2.
5. Make another plot containing: (a) instantaneous 1gSAR versus time determined in Step 3, (b) computed time-averaged 1gSAR versus time determined in Step 3, and (c) corresponding regulatory $1gSAR_{limit}$ of 1.6W/kg.

The validation criteria is, at all times, the time-averaged 1gSAR versus time shall not exceed the regulatory $1gSAR_{limit}$ of 1.6W/kg.

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